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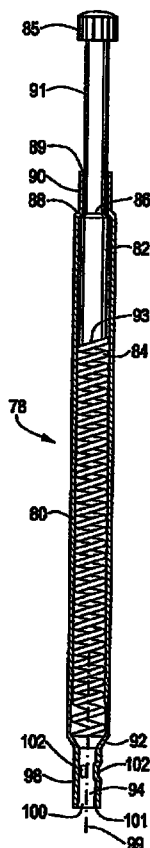
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(54) Title: **TEST PROBE AND CONNECTOR**



(57) Abstract: An improved probe (78) includes a conductive tubular housing (80) or body containing a coil spring (84) and a conductive plunger (82) movable in the housing (80) and having a contact tip (85) outwardly extending from one end of the housing (80). The plunger (82) and tip (85) are urged to a normally outward position by the bias force of the spring (84). The opposite end of the housing has an opening for mating with a conductive pin of a connector. The connector (96, 97) is retained in a mounting plate (52) of an associated fixture (40) and has terminal ends of desired configuration. The terminal end may include a wire-wrap pin, a crimp type terminal (113) for attachment to a wire (110), or the terminal may include a spring loaded pin (84) for engagement with an associated electrical contact. An air tight seal (170) may be provided between the probe and the connector and the connector may be mounted in a mounting such that when vacuum is applied to an associated test fixture (40), air cannot be drawn through the fixture or through the body of the probe.

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